

# **CoolMOS**<sup>™</sup> **Power Transistor**

#### **Features**

- Lowest figure-of-merit R<sub>ON</sub>xQ<sub>a</sub>
- Ultra low gate charge
- Extreme dv/dt rated
- · High peak current capability
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Pb-free lead plating; RoHS compliant

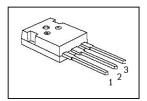
## **CoolMOS CP** is specially designed for:

Hard switching SMPS topologies

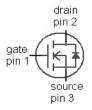
## **Product Summary**

V <sub>DS</sub> @ T <sub>j,max</sub>	650	V
R <sub>DS(on),max</sub>	0.299	Ω
Q <sub>g,typ</sub>	22	nC

#### PG-TO247-3-1



Туре	Package	Ordering Code	Marking
IPW60R299CP	PG-TO247-3-1	SP000103251	6R299P



# **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	11	А
		T <sub>C</sub> =100 °C	7	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	34	
Avalanche energy, single pulse	E <sub>AS</sub>	I <sub>D</sub> =4.4 A, V <sub>DD</sub> =50 V	290	mJ
Avalanche energy, repetitive $t_{AR}^{(2),3)}$	E <sub>AR</sub>	/ <sub>D</sub> =4.4 A, V <sub>DD</sub> =50 V	0.44	
Avalanche current, repetitive $t_{\rm AR}^{\ 2),3)}$	I <sub>AR</sub>		4.4	A
MOSFET dv/dt ruggedness	dv/dt	V <sub>DS</sub> =0480 V	50	V/ns
Gate source voltage	$V_{\rm GS}$	static	±20	V
		AC (f>1 Hz)	±30	
Power dissipation	P <sub>tot</sub>	T <sub>C</sub> =25 °C	96	W
Operating and storage temperature	$T_{\rm j}$ , $T_{\rm stg}$		-55 150	°C
Mounting torque		M3 and M3.5 screws	60	Ncm



# **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous diode forward current	Is	Т <sub>С</sub> =25 °С	6.6	Α
Diode pulse current <sup>2)</sup>	I <sub>S,pulse</sub>	7 <sub>C</sub> -23 G	34	
Reverse diode dv/dt <sup>4)</sup>	dv/dt		15	V/ns

Parameter	Symbol Conditions	Values			Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R <sub>thJC</sub>		-	-	1.3	K/W
Thermal resistance, junction - ambient	$R_{ m thJA}$	leaded	-	-	62	
Soldering temperature, wavesoldering only allowed at leads	$T_{sold}$	1.6 mm (0.063 in.) from case for 10 s	-	-	260	°C

# **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0 V, I <sub>D</sub> =250 μA	600	1	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 0.44 \text{ mA}$	2.5	3	3.5	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =600 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C	-	-	1	μΑ
		V <sub>DS</sub> =600 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =150 °C	-	10	-	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10 V, I <sub>D</sub> =6.6 A, T <sub>j</sub> =25 °C	-	0.27	0.299	Ω
		V <sub>GS</sub> =10 V, I <sub>D</sub> =6.6 A, T <sub>j</sub> =150 °C	-	0.73		
Gate resistance	R <sub>G</sub>	f=1 MHz, open drain	-	1.9	-	Ω



Parameter	Symbol Conditions	Values			Unit	
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =100 V,	-	1100	-	pF
Output capacitance	C oss	f=1 MHz	-	60	-	
Effective output capacitance, energy related <sup>5)</sup>	C o(er)	V <sub>GS</sub> =0 V, V <sub>DS</sub> =0 V to 480 V	-	46	-	
Effective output capacitance, time related <sup>6)</sup>	C <sub>o(tr)</sub>		-	120	-	
Turn-on delay time	t <sub>d(on)</sub>		-	10	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =400 V,	-	5	-	
Turn-off delay time	$t_{\text{d(off)}}$	$V_{\rm GS}$ =10 V, $I_{\rm D}$ =6,6 A, $R_{\rm G}$ =4,3 $\Omega$	-	40	-	
Fall time	t <sub>f</sub>		1	5	-	
Gate Charge Characteristics						
Gate to source charge	Q <sub>gs</sub>		-	5	-	nC
Gate to drain charge	Q <sub>gd</sub>	V <sub>DD</sub> =400 V, I <sub>D</sub> =6.6 A,	-	7.6	-	
Gate charge total	Qg	V <sub>GS</sub> =0 to 10 V	-	22	29	
Gate plateau voltage	V <sub>plateau</sub>		-	5.0	-	V
Reverse Diode						
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =6.6 A, T <sub>j</sub> =25 °C	-	0.9	1.2	V
Reverse recovery time	t <sub>rr</sub>		-	300	-	ns
Reverse recovery charge	Q <sub>rr</sub>	$V_R$ =400 V, $I_F$ = $I_S$ , $di_F$ / $dt$ =100 A/ $\mu$ s	-	3.9	-	μC
Peak reverse recovery current	I <sub>rrm</sub>		-	26	-	Α

<sup>1)</sup> J-STD20 and JESD22

 $<sup>^{2)}</sup>$  Pulse width  $t_{\,\mathrm{p}}$  limited by  $T_{\,\mathrm{j,max}}$ 

 $<sup>^{3)}</sup>$  Repetitive avalanche causes additional power losses that can be calculated as  $P_{\rm AV}$  =  $E_{\rm AR}$   $^*$  f.

 $<sup>^{4)}</sup> I_{SD} <= I_D, \ di/dt <= 200 A/\mu s, \ V_{DClink} = 400 V, \ V_{peak} < V_{(BR)DSS}, \ T_j < T_{jmax}, \ identical \ low \ side \ and \ high \ side \ switch.$ 

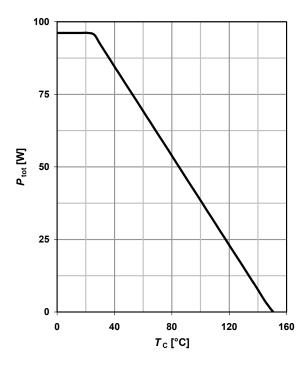
 $<sup>^{5)}</sup>$   $C_{\rm o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 80%  $V_{\rm DSS}$ .

 $<sup>^{6)}</sup>$   $C_{\text{o(tr)}}$  is a fixed capacitance that gives the same charging time as  $C_{\text{oss}}$  while  $V_{\text{DS}}$  is rising from 0 to 80%  $V_{\text{DSS}}$ .



## 1 Power dissipation

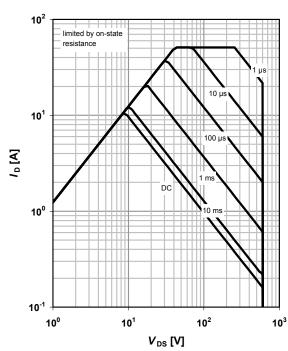
$$P_{\text{tot}}$$
=f( $T_{\text{C}}$ )



## 2 Safe operating area

 $I_D$ =f( $V_{DS}$ );  $T_C$ =25 °C; D=0

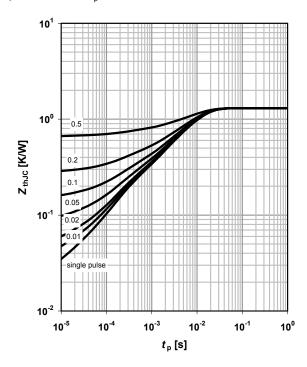
parameter: t<sub>p</sub>



# 3 Max. transient thermal impedance

 $Z_{thJC}$ =f( $t_P$ )

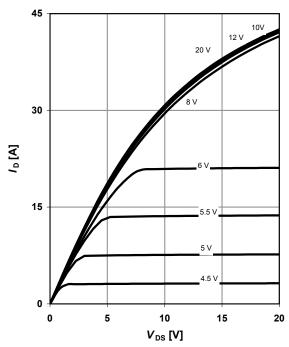
parameter:  $D=t_p/T$ 



# 4 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$ 

parameter: V<sub>GS</sub>

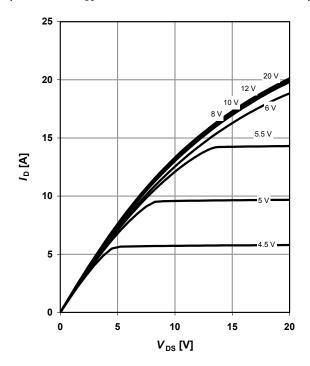




## 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 150 °C$ 

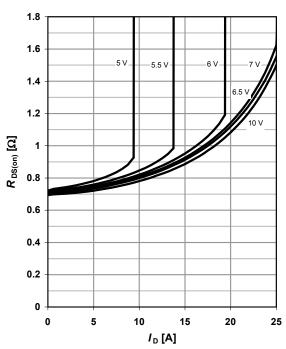
parameter:  $V_{\rm GS}$ 



## 6 Typ. drain-source on-state resistance

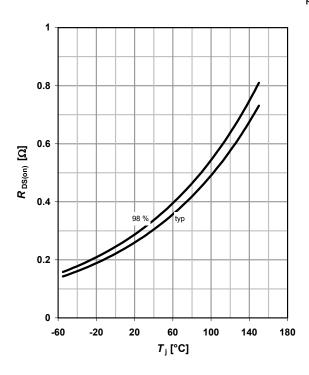
 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =150 °C

parameter:  $V_{\rm GS}$ 



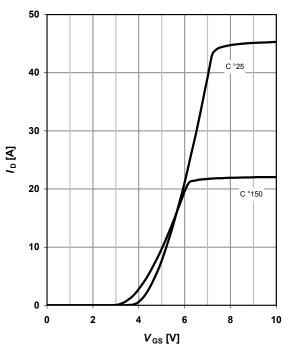
## 7 Drain-source on-state resistance

 $R_{DS(on)} = f(T_i); I_D = 6.6 \text{ A}; V_{GS} = 10 \text{ V}$ 



# 8 Typ. transfer characteristics

 $I_{\rm D}$ =f( $V_{\rm GS}$ );  $|V_{\rm DS}|$ >2 $|I_{\rm D}|R_{\rm DS(on)max}$ parameter:  $T_{\rm j}$ 

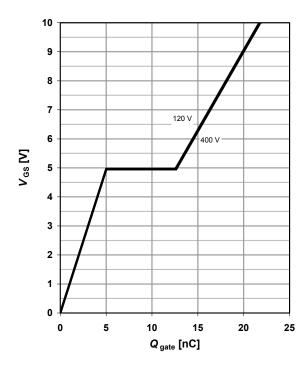




# 9 Typ. gate charge

 $V_{\rm GS}$ =f(Q  $_{\rm gate}$ );  $I_{\rm D}$ =6.6 A pulsed

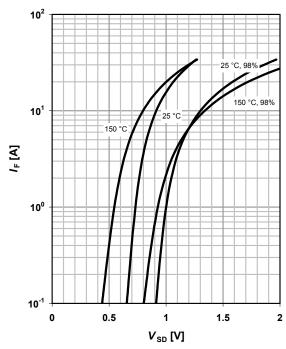
parameter:  $V_{\rm DD}$ 



#### 10 Forward characteristics of reverse diode

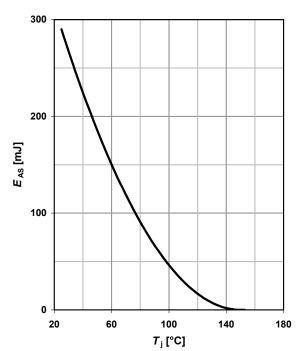
 $I_F = f(V_{SD})$ 

parameter:  $T_j$ 



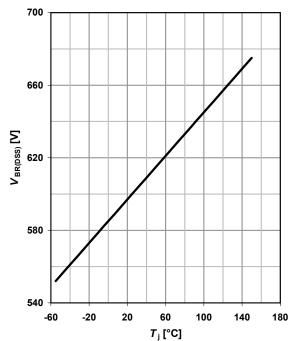
# 11 Avalanche energy

$$E_{AS}$$
=f( $T_i$ );  $I_D$ =4.4 A;  $V_{DD}$ =50 V



# 12 Drain-source breakdown voltage

$$V_{BR(DSS)}$$
=f( $T_j$ );  $I_D$ =0.25 mA



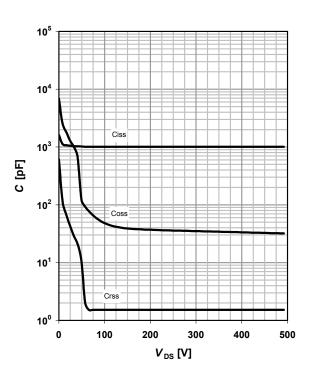


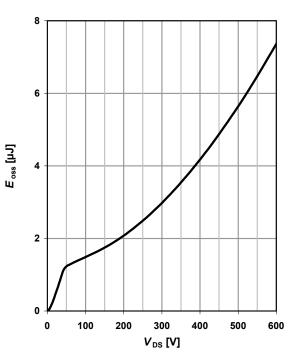
# 13 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 

# 14 Typ. Coss stored energy

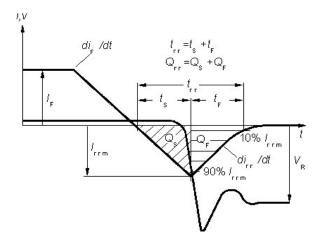
$$E_{oss} = f(V_{DS})$$





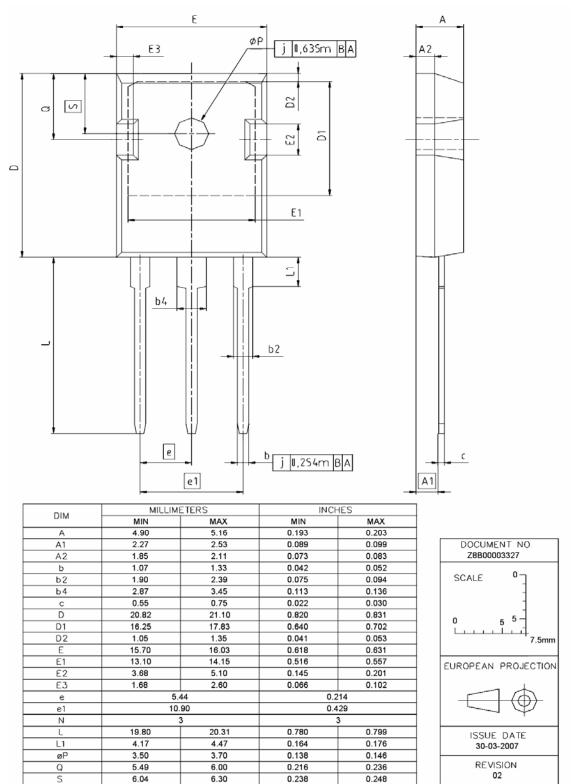


# **Definition of diode switching characteristics**





#### PG-TO247-3-21-41: Outlines



Dimensions in mm/inches



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